

Notice of References Cited

Application/Control No.

10/572,505

Applicant(s)/Patent Under
Reexamination
SAKURAI ET AL.

Examiner

MATTHEW D. MATZEK

Art Unit

1794

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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	E	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2003-082533	03-2003	Japan	Tanaka et al.	D01F 009/127
	O					
	P					
	Q					
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NON-PATENT DOCUMENTS

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